

| DHV 102 | Solid State Device Physics | | Τ | Р | С |
|-----------------------------|-------------------------------|---|---|---|---|
| Solid State Device I hysics | | 3 | 0 | 0 | 3 |
| Co-requisite: | NIL | | | | |
| Prerequisite: | Engineering Physics (PHY 101) | | | | |
| Data Book / | NII | | | | |
| Codes/Standards | INIL | | | | |
| Course Category | CORE | | | | |
| Course designed by | Department of Physics | | | | |
| Approval | | | | | |

PURPOSEThe course aims to cover the fundamental formalism and applications of Physics. It
mainly includes introduction to modern physics, fundamentals of quantum
mechanics, solid state physics and devices

| LEA | LEARNING OBJECTIVES | | | | | 5 | |
|------|---|--|--|--|--|---|--|
| At t | At the end of the course, student will be able to | | | | | | |
| 1. | apply the fundamental concepts of modern physics and explain physics phenomenon | | | | | | |
| 2. | students' physical intuition and thinking process through understanding the theory | | | | | | |
| 3. | Understand basics of solid state physics and functioning of devices | | | | | | |

| Session | Description of Topic | Contact hours | C-D-I-O | IOs | Reference |
|---------|--|------------------|---------|-----|-----------|
| | UNIT I – Quantum Mechanics and Application | 9 | | | |
| 1. | Light as particle: Photoelectric effect, idea of photon | 1 | С | | 1,2,3 |
| 2. | Wave particle duality Matter waves - De Broglie hypothesis | 1 | С | | 1,2,3 |
| 3. | Postulates of quantum mechanics, Wave function and its physical interpretation | 1 | С | | 1,2,3 |
| 4. | Heisenberg's uncertainty principle-qualitative discussion | 1 | С | | 1,2,3 |
| 5. | Schrodinger's equation | 1 | C-D | | 1,2,3 |
| 6. | Probability current density, Equation of continuity, and its physical significance | 1 | C-D | | 1,2,3 |
| 7. | Free particle, Particle in infinitely deep potential well (one - dimension) | 1 | D | | 1,2,3 |



| 8. | Step potential, Potential barrier (Qualitative discussion).Particle in three dimensional rigid box | 1 | D | 1,2,3 |
|-----|---|---|-----|-------|
| 9. | Barrier penetration and tunneling effect | 1 | D-I | 1,2,3 |
| | UNIT II – Energy Bands and Charge Carriers in Semiconductors | 9 | | |
| 10. | Crystal Lattices, Periodic Structures Cubic Lattices its plane and directions | 1 | D | 1,2,3 |
| 11. | Energy bands: Metals - semiconductors and insulators, direct and indirect semiconductors | 1 | D | 1,2,3 |
| 12. | Electrons and holes- intrinsic and extrinsic material, Doped materials - n-type material and p-type semiconductor material | 1 | D-I | 1,2,3 |
| 13. | Electrons and holes in Quantum wells | 1 | D-I | 1,2,3 |
| 14. | The Fermi Level, Electron and hole concentrations at equilibrium, Temperature dependence of carrier concentrations | 1 | D | 1,2,3 |
| 15. | Electrical conductivity and mobility, Drift and resistance, Effects of temperature and doping on mobility | 1 | D-I | 1,2,3 |
| 16. | Carrier Lifetime - Direct recombination, Indirect recombination; Trapping | 1 | D | 1,2,3 |
| 17. | Diffusion and drift of Carriers, Built-in electric Fields, Hall effects | 1 | D | 1,2,3 |
| 18. | Diffusion and recombination, The continuity equation | 1 | D-I | 1,2,3 |
| | UNIT III: PN Junctions | 9 | | |
| 19. | Steady state carrier injection; Diffusion length | 1 | С | 1,2,3 |
| 20. | Fabrication of p-n Junctions | 1 | C-D | 1,2,3 |
| 21. | Equilibrium condition of p-n Junctions | 1 | C-D | 1,2,3 |
| 22. | The Contact potential, Equilibrium Fermi levels, Space charge and capacitance of p-n a junction | 1 | C-D | 1,2,3 |
| 23. | Qualitative description of current flow at a forward biased p-n junctions | 1 | C-D | 1,2,3 |
| 24. | Carrier injection from metal contact | 1 | D | 1,2,3 |
| 25. | Reverse-biased p-n junctions; Steady state conditions | 1 | D | 1,2,3 |
| 26. | Zener breakdown and Avalanche breakdown, Voltage rectifiers | 1 | D | 1,2,3 |
| 27. | Metal–Semiconductor Junctions: Schottky Barriers, Rectifying Contacts, Ohmic Contacts | 1 | D | 1,2,3 |
| | UNIT-IV: Transistors | 9 | | |
| 28. | Bipolar Junction and Field Effect Transistor Operation – (BJT and FET) The Load Line, Amplification and Switching | 1 | С | 1,2,3 |



| 29. | The Junction fabrication BJT and FET | 1 | C-D | | 1,2,3 | |
|-----|---|----|-----|--|---------|--|
| 30. | The Metal–Semiconductor FET | 1 | C-D | | 1,2,3 | |
| 31. | The Metal–Insulator–Semiconductor FET Basic Operation and Fabrication | 1 | C-D | | 1,2,3 | |
| 32. | The Ideal MOS Capacitor, MOS capacitance – voltage Analysis | 1 | D | | 1,2,3 | |
| 33. | Time-dependent capacitance measurements, Current–voltage characteristics of MOS Gate Oxides | 1 | D-I | | 1,2,3 | |
| 34. | MOS Field-effect Transistor - Output characteristics, Transfer characteristics | 1 | C-D | | 1,2,3 | |
| 35. | Short channel MOSFET I–V characteristics, Equivalent circuit for the MOSFET | 1 | D | | 1,2,3 | |
| 36. | Frequency Limitations of Transistors | 1 | D-I | | 1,2,3 | |
| | UNIT V: Optoelectronic Devices | 9 | | | | |
| 37. | Steady State Carrier Generation; Quasi-Fermi Levels | 1 | С | | 1,2,3,4 | |
| 38. | Photoconductive devices, Current and voltage in an illuminated p-n junction | 1 | C-D | | 1,2,3,4 | |
| 39. | Solar Cells and Photodetectors | 1 | D-I | | 1,2,3,4 | |
| 40. | Light-emitting diodes | 1 | D | | 1,2,3,4 | |
| 41. | Metastable state, Population inversion and Einstein's A and B coefficient | 1 | C-D | | 1,2,3,4 | |
| 42. | Basic of semiconductor laser | 1 | С | | 1,2,3,4 | |
| 43. | Population Inversion at a Junction, Emission Spectra for p-n junction Lasers | 1 | C-D | | 1,2,3,4 | |
| 44. | Materials for Semiconductor Lasers, Fabrications | 1 | D-I | | 1,2,3,4 | |
| 45. | Heterojunction Lasers | 1 | D | | 1,2,3,4 | |
| | Total contact hours | 45 | | | | |

| | LEARNING RESOURCES | | | | | | | | |
|---|---|--|--|--|--|--|--|--|--|
| | TEXT BOOKS/REFERENCE BOOKS/OTHER READING MATERIAL | | | | | | | | |
| 1 | Solid State Electronic Devices - Ben G. Streetman and Sanjay Kumar Banerjee, VII Edition (2015), Publisher – PEARSON | | | | | | | | |
| 2 | Semiconductor Physics and Devices - Donald A. Neamen, Dhrubes Biswas, V Edition (2012), Publisher – Mc Graw Hill (Indian) | | | | | | | | |
| 3 | Concept of Modern Physics - Arthur Besier, Shobhit Mahajan, S Rai, 2017 Edition, Publisher - Tata McGraw Hill | | | | | | | | |
| 4 | Optics - Ajay Ghatak, Fifth Edition (2010), Publisher - Mcgraw Hill | | | | | | | | |



| 5 | Fiber optics and Lasers: The two revolutions - A. Ghatak, K. Tyagarajan (2006) |
|---|--|
| 5 | Publisher -Macmillan |

| Course nature | | | | | Theory | | | | | |
|---|--------------------|------------|-------------|-------|--------|-------|--|--|--|--|
| Assessment Method – Theory Component (Weightage 100%) | | | | | | | | | | |
| In- | Assessment tool | Mid Term I | Mid Term II | CLA I | CLA II | Total | | | | |
| semester | Weightage | 15% | 15% | 10% | 10% | 50% | | | | |
| End semester examination Weightage : | | | | | | | | | | |



| DUV 1021 | SOLID STATE DEVICE PHYSICS | L | Τ | P | С |
|--------------------|----------------------------|---|---|---|---|
| FHI 102L | LABORATORY | 0 | 0 | 2 | 1 |
| Co-requisite: | NIL | | | | |
| Prerequisite: | PHY 101L | | | | |
| Data Book / | NII | | | | |
| Codes/Standards | INIL | | | | |
| Course Category | CORE | | | | |
| Course designed by | Department of Physics | | | | |
| Approval | | | | | |

| PU E | RPOS | OS The course aims to cover the application of fundamental formalism of Physics. It mainly includes modern physics, wave and optics, fiber optics, solid state physics. | | | | | | | |
|---------|---|--|--|--|--|--|--|--|--|
| LE | LEARNING OBJECTIVES STUDENT OUTCOMES | | | | | | | | |
| At | the end o | f the course, student will be able to | | | | | | | |
| 1. | Understa | nd basic equipment operation and analysis | | | | | | | |
| 2. | Correlate | e fundamental concept of physics to laboratory experiments | | | | | | | |

| Sl. No | Description of Experiments | Contact hours | C-D-I-O | IOs | Reference |
|-----------|--|------------------|---------|-----|-----------|
| 1 | Measurement of Planck's constant by Cs photocell | 1 | I-O | | 1, 2 |
| 2 | To record the Franck-Hertz characteristic curve for neon emission | 1 | I-O | | 1, 2 |
| 3 | Determine charge carrier type and concentration of a given semiconductor using Hall Effect | 2 | I-O | | 1, 2 |
| 4 | Four-probe Resistivity Measurement | 1 | I-O | | 1, 2 |
| 5 | Circuit Simulation Tutorials for p-n diodes (LTspice) | 1 | I-O | | |
| 6 | Circuit Simulation Tutorials for Zener diodes (LTspice) | 1 | I-O | | |
| 7 | Circuit Simulation Tutorials for Bipolar Junction Transistor (LTspice) | 1 | I-O | | 1, 2 |
| 8 | Circuit Simulation Tutorials for MOSFET (LTspice) | 1 | I-O | | 1, 2 |
| 9 | Determination of the beam quality factor (M- parameter) of a given semiconductor laser | 1 | I-O | | 1, 2 |
| 10 | To determine the wavelength of a given semiconductor laser lights with the diffraction patterns by single slit and double slit | 1 | I-O | | 1, 2 |
| 11 | a) To measure the photo-current as a function of the irradiance at constant voltage b) Current-voltage and current-load characteristics of a solar cell as a function of the irradiance | 1 | I-O | | 1, 2 |
| 12 | To determine the wavelength of a semiconductor | 2 | I-O | | 1, 2 |



| 13 | laser using the Michelson interferometera) Determination the wavelength of He-Ne laserusing diffraction grating | 1 | I-O | 1 2 |
|----|---|---|-----|------|
| 15 | b) Determination the particle size of a given powder | 1 | 1-0 | 1, 2 |
| | Total contact hours (Including demo and repeat labs) | | 15 | |

LEARNING RESOURCES

| | TEXT BOOKS/REFERENCE BOOKS/OTHER READING MATERIAL |
|---|--|
| 1 | Physics for Scientist and Engineers, Ninth edition (2017) - Raymond A. Serway, John W. Jewett (Publisher - Cengage India Private Limited)) |
| 2 | Physics laboratory manuals |

| Course nat | | | | | | | |
|--|--------------------|------------------------|-------------------------|----------------------|-------|--|--|
| | | | | | | | |
| Assessment Method – Practical Component (Weightage 100%) | | | | | | | |
| In- semester | Assessment tool | Lab performanc e | Practical model exam | Observatio n note | Total | | |
| | Weightage | 20% | 20% | 10% | 50% | | |
| | | | | | | | |
| End semes | ter examinatio | on Weightage | : | | 50% | | |